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DVClub Europe

Formal fault analysis for ISO 26262 fault metrics on real world designs

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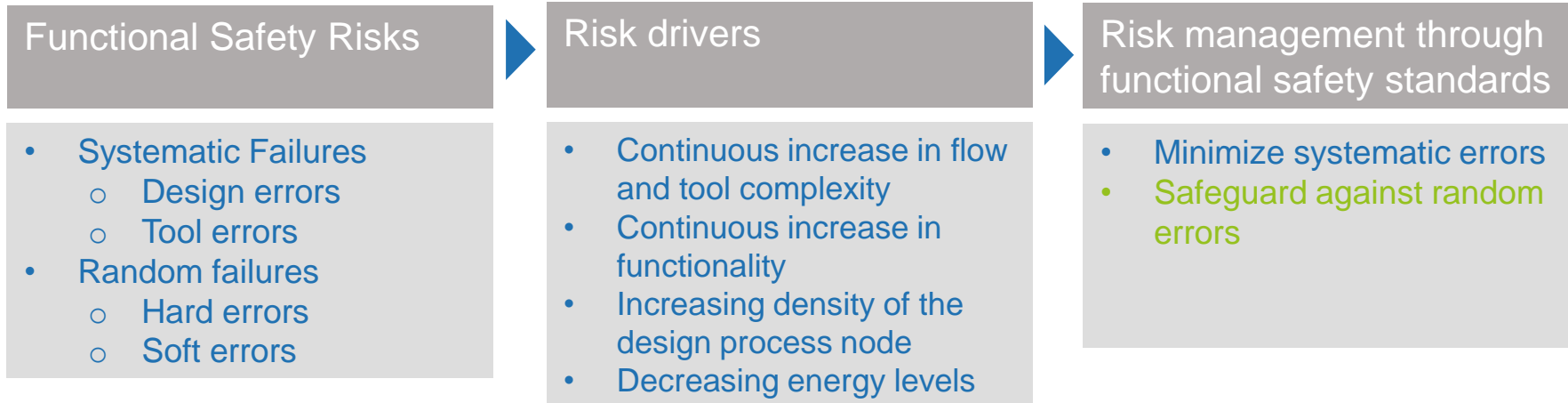
Product Manager Functional Safety

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Introduction Functional Safety

The objective of functional safety is freedom from unacceptable risk of physical injury or of damage to the health of people either directly or indirectly.





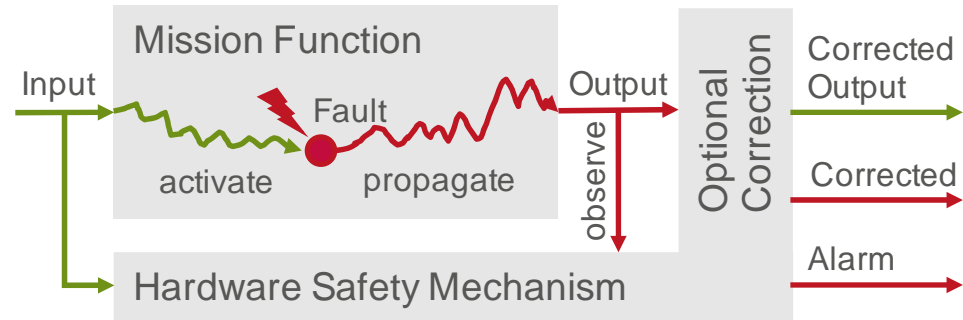
Safeguard Against Random Errors

Fault lifecycle:

- Activated (reached)
- Propagated to mission output
- Observed by safety mechanism
- Detected/Corrected by safety mechanism

Faults are caused by hard or soft errors

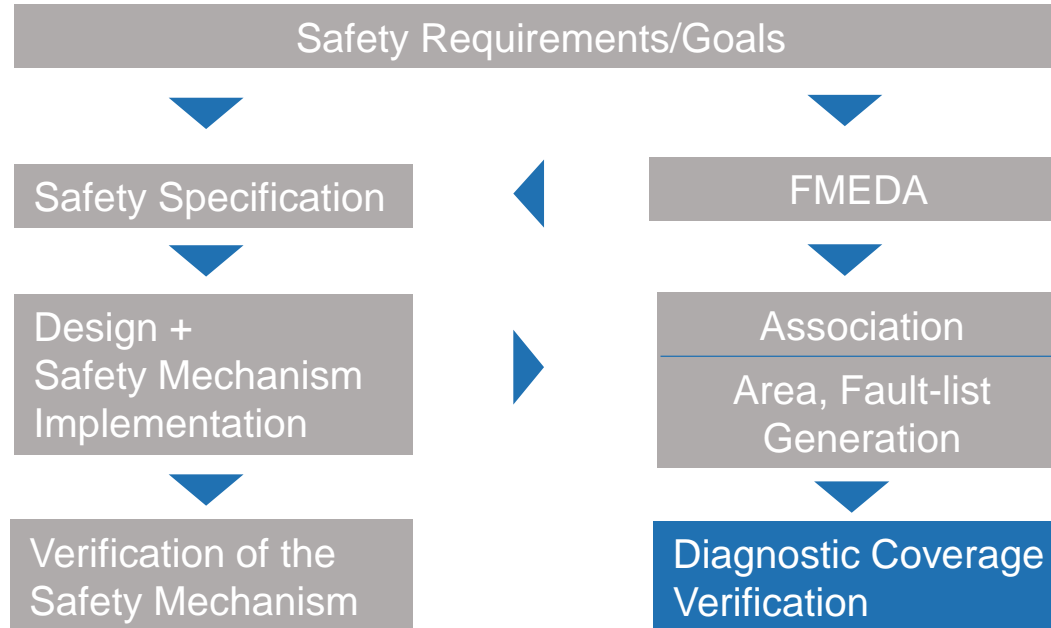
- Permanent (Latch up, bridging)
 - StuckAt's
- Transient
 - Single Event Faults
- Intermittent



ISO 26262 requires

- Verification of the safety mechanism
- Diagnostic coverage of the safety mechanism

Safety Flow for Random Errors





Single Point Fault Metric

ISO 26262 provides and requires the framework

Safe faults

- Not in safety relevant parts of the logic
- In safety relevant logic but unable to impact the design function (cannot violate a safety goal)

Single point faults

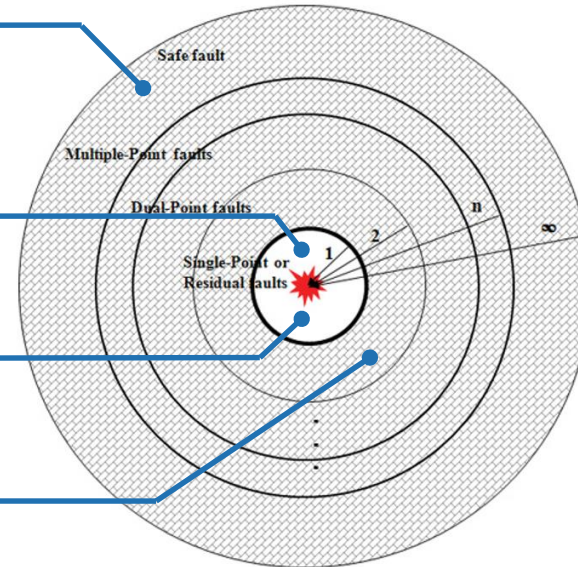
- Dangerous, can violate the safety goal and no safety mechanism

Residual faults

- Dangerous, can violate the safety goal and escape the safety mechanism

Multipoint faults

- Can violate the safety goal but are observed by a safety mechanism
- Sub-classified as “detected”, “perceived” or “latent”



Single-Point Fault Metric

$$= \frac{\text{Single-Point or Residual faults}}{\text{Total faults}}$$

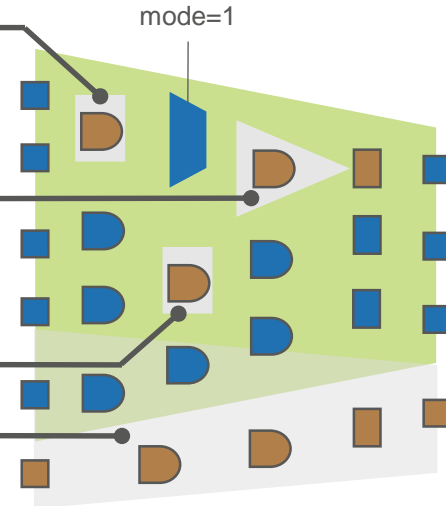
up to 99% required

Diagram Courtesy International Standards Organization (ISO)

Reasons for Safe Faults

Considering StuckAt faults only

- Safe faults due to static IC operation modes
 - Debug mode disabled
 - Test logic
- Explicit redundancy in hardware masks the effect of fault
 - Performance impact only
 - States never used in safe operation mode
- Truly redundant logic like synthesis deficiencies
- Safety unrelated logic
 - Design parts which do not impact the safety goal



All safe faults cannot propagate to observation points

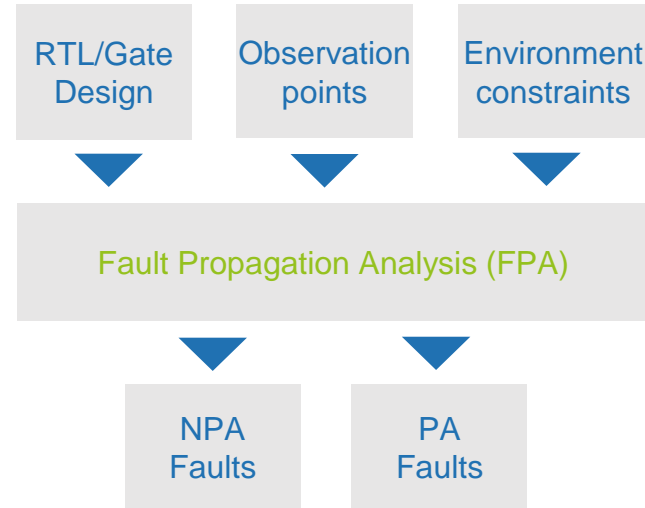
- Mission outputs
- Internal registers



Formal Fault Propagation Analysis

No formal knowledge required

- Automatically classifies faults into
 - Non-propagatable faults (safe)
 - Propagatable faults
 - Dangerous (single point & residual)
 - Potentially detected (multipoint detected)
- Can be performed at RT and gate level
- Only needs very limited additional input
 - Observation points define where faults can propagate (default is primary outputs)
 - Environment constraints, assign values to test pins, debug modes and control registers
- Fault lists can be provided by the user or generated by the tool
 - StuckAt fault model supported

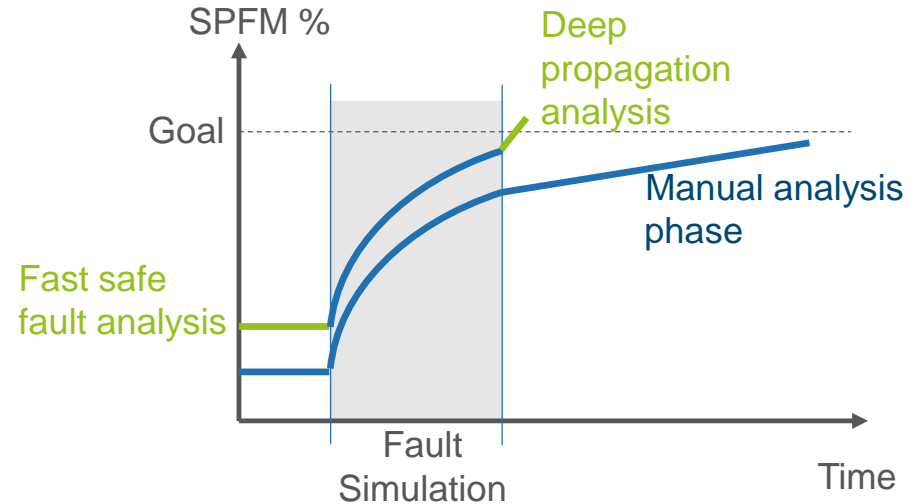




Use Case: Formally Identify Safe Faults

The more the better

- Today engineers use fault simulation to determine fault metrics
- What if the fault simulation does not achieve the desired metric?
 - Manually identify safe faults
 - Improve safety mechanism, re-simulate ...
 - How many safe faults are there?
- Formal fault propagation identifies safe faults automatically
 - Fast up front analysis to increase the safe fault population
 - Deep propagation analysis to close the remaining gap
 - Reduce time and increase confidence



Only formal technology can efficiently combine the design and environmental constraints to bring fault analysis to the next level.

Fast Fault Propagation Analysis

- Always executed for all possible fault locations
- Shall be executed before fault simulation and/or deep fault propagation analysis

	RTL example	Gate level
Description	open core processor ~10k lines / 794 registers 12.260 faults	summary of field data up to 2 million faults
Performance – CPU time	2 minutes	up to several hours
Result	3257 (26%) safe faults	up to 14% safe fault (including untestable)

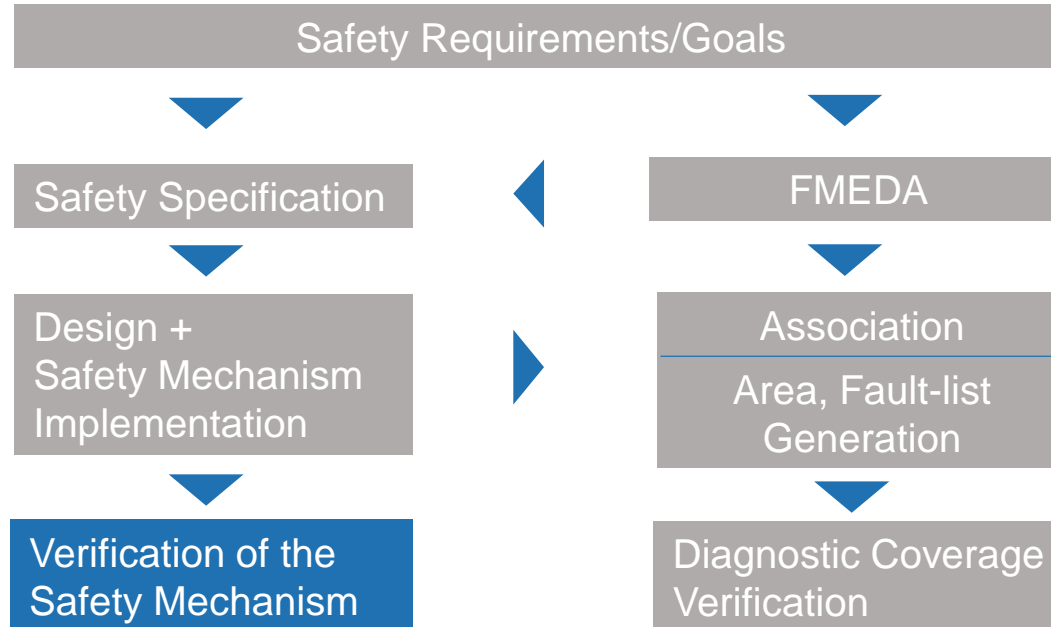


Deep Fault Propagation Analysis

- Requires a fault list as input
- Often executed in fault sampling mode or on smaller sets of faults

	RTL example	Gate level
Description	open core processor ~10k lines / 794 registers 12.260 faults	summary of field data up to 2 million faults
Performance – CPU time	most safe faults typically proven in 20-30 sec (some faults cannot be proven within time budget)	several seconds to minutes per fault (some faults cannot be proven within time budget)
Result	~13% safe faults (after fast fault analysis, NOTE: design not “optimized” by synthesis)	0.3-2.1% safe faults (after fast analysis or fault simulation)

Safety Flow for Random Errors



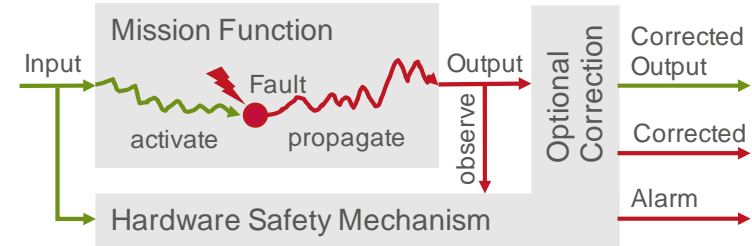


Verification of the Hardware Safety Mechanism

ABV with fault injection

Problem

- Hardware safety mechanism is inactive unless a fault occurs
 - ISO 26262 recommends fault injection for verification
- Fault Injection complexity for bit vectors:
 - 2^{width} possible data input combinations
 - $(width)$ 1-bit errors
 - $(width * width - 1)$ 2-bit errors
- Simulation based verification hits its limits
 - Must anticipate all possible input combination
 - Propagate all possible faults
 - Check the outcome



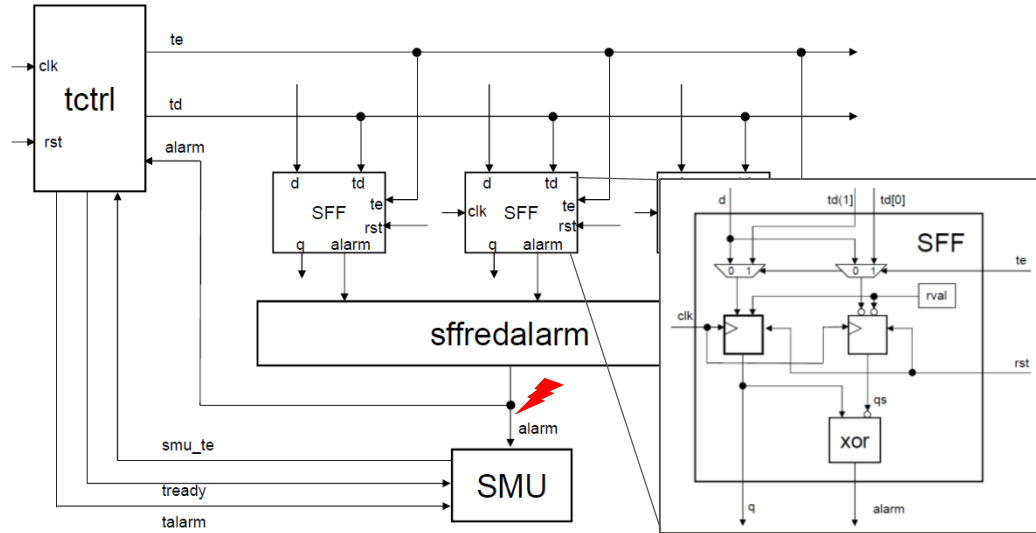
Solution

- Formal verification with fault injection
- Trivial output assertion
 - No “Alarm” when no fault is injected
 - Always expect “Alarm” when fault is injected
- Inputs must be constrained
 - Avoid illegal input pattern when no fault is injected and no alarm is expected



Formal Safety Verification with Fault Injection

Where the rubber meets the road



OneSpin 360™ DV-Verify with fault injection

- Exhaustive fault activation including multiples
- Efficient modeling of faults and specification of requirements
- Highly automated
- Handling large blocks and huge number of faults simultaneously

H. Busch, Infineon Technologies, “Formal Safety Verification of Automotive Microcontroller Parts”, ZuE2012, Bremen



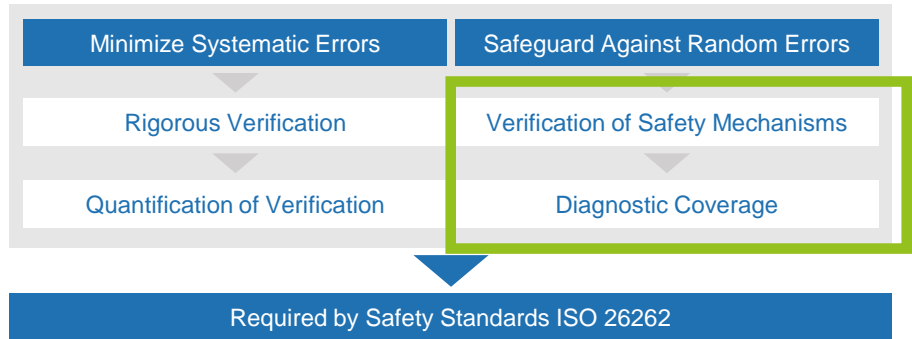
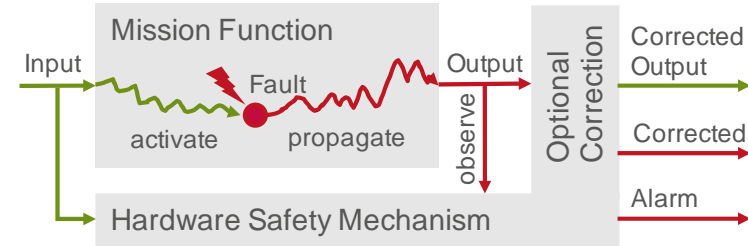
Safety Critical Verification

Assuring High Reliability

Meeting tough functional safety standards, e.g. ISO 26262

Minimize systematic errors & protect against random faults

- Rigorous, exhaustive formal
- Industry-leading quantification and qualification of formal properties
- Efficient verification of functional safety mechanism
- Precise diagnostic coverage through formal fault analysis





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Thank You!

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